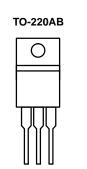


# N-Channel 650 V (D-S) MOSFET

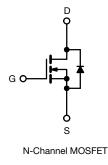
PRODUCT SUMMARY				
V <sub>DS</sub> (V) at T <sub>J</sub> max.	650			
R <sub>DS(on)</sub> max. (Ω) at 25 °C	V <sub>GS</sub> = 10 V 0.34			
Q <sub>g</sub> max. (nC)	106			
Q <sub>gs</sub> (nC)	14			
Q <sub>gd</sub> (nC)	33			
Configuration	Single			

#### **FEATURES**

- Reduced  $t_{rr}$ ,  $Q_{rr}$ , and  $I_{RRM}$
- Low figure-of-merit (FOM) Ron x Qg
- Low input capacitance (Ciss)
- Low switching losses due to reduced Q<sub>rr</sub>
- Ultra low gate charge (Q<sub>g</sub>)
- Avalanche energy rated (UIS)



GDS



ABSOLUTE MAXIMUM RATINGS (T <sub>C</sub>	= 25 °C, un	less otherwis	se noted)			
PARAMETER			SYMBOL	LIMIT	UNIT	
Drain-Source Voltage			V <sub>DS</sub>	650	V	
Gate-Source Voltage			V <sub>GS</sub>	± 30		
Continuous Drain Current (T <sub>.1</sub> = 150 °C)	V <sub>GS</sub> at 10 V	$T_{C} = 25 \text{ °C}$ $T_{C} = 100 \text{ °C}$	- I <sub>D</sub>	18		
Continuous Drain Current $(1j = 150^{\circ} C)$				16	А	
Pulsed Drain Current <sup>a</sup>			I <sub>DM</sub>	53		
Linear Derating Factor				1.7	W/°C	
Single Pulse Avalanche Energy <sup>b</sup>			E <sub>AS</sub>	367	mJ	
Maximum Power Dissipation			PD	208	W	
Operating Junction and Storage Temperature Range			T <sub>J</sub> , T <sub>stg</sub>	-55 to +150	°C	
Drain-Source Voltage Slope $T_J = 125 \text{ °C}$		dV/dt	37	V/ns		
Reverse Diode dV/dt <sup>d</sup>			31			
Soldering Recommendations (Peak Temperature) c for 10 s		10 s		300	°C	

#### Notes

a. Repetitive rating; pulse width limited by maximum junction temperature. b. V<sub>DD</sub> = 50 V, starting T<sub>J</sub> = 25 °C, L = 28.2 mH, R<sub>g</sub> = 25  $\Omega$ , I<sub>AS</sub> = 5.1 A. c. 1.6 mm from case. d. I<sub>SD</sub> ≤ I<sub>D</sub>, dl/dt = 100 A/µs, starting T<sub>J</sub> = 25 °C.





PARAMETER	SYMBOL	TYP.		MAX.			UNIT	
Maximum Junction-to-Ambient	R <sub>thJA</sub>	-		62		°C/W		
Maximum Junction-to-Case (Drain)	R <sub>thJC</sub>	-		0.5				
			•					
SPECIFICATIONS (T <sub>J</sub> = 25 °C, u	nless otherw	ise noted)						
PARAMETER	SYMBOL		T CONDITIONS		MIN.	TYP.	MAX.	UNI
Static		1		1		<u> </u>	<b>I</b>	
Drain-Source Breakdown Voltage	V <sub>DS</sub>	V <sub>GS</sub> :	= 0 V, I <sub>D</sub> = 250 μA		650	-	-	V
V <sub>DS</sub> Temperature Coefficient	$\Delta V_{DS}/T_{J}$	Referenc	e to 25 °C, I <sub>D</sub> = 1 r	nA	-	0.67	-	V/°C
Gate-Source Threshold Voltage (N)	V <sub>GS(th)</sub>	V <sub>DS</sub> =	= V <sub>GS</sub> , I <sub>D</sub> = 250 μA		2.5	-	4	V
Osta Osumas Laskana			$V_{GS} = \pm 20 V$		-	-	± 100	nA
Gate-Source Leakage	I <sub>GSS</sub>		$V_{GS} = \pm 30 \text{ V}$		-	-	± 1	μA
Zere Cete Veltege Drein Orment	I	V <sub>DS</sub> =	=650 V, V <sub>GS</sub> = 0 V		-	-	1	
Zero Gate Voltage Drain Current	IDSS	V <sub>DS</sub> = 520 \	$V, V_{GS} = 0 V, T_{J} = 1$	25 °C	-	-	500	μA
Drain-Source On-State Resistance	R <sub>DS(on)</sub>	$V_{GS} = 10 V$	I <sub>D</sub> = 11 A		-	0.34	-	Ω
Forward Transconductance	9 <sub>fs</sub>	V <sub>DS</sub>	= 30 V, I <sub>D</sub> = 11 A		-	7.0	-	S
Dynamic		•		•		•	•	•
Input Capacitance	C <sub>iss</sub>		V <sub>GS</sub> = 0 V,		-	4826	-	
Output Capacitance	C <sub>oss</sub>	$V_{GS} = 0 V,$ $V_{DS} = 100 V,$			-	456	-	-
Reverse Transfer Capacitance	C <sub>rss</sub>		f = 1 MHz		-	210	-	
Effective Output Capacitance, Energy Related <sup>a</sup>	C <sub>o(er)</sub>	$V_{DS} = 0 V$ to 520 V, $V_{GS} = 0 V$		-	84	-	pF	
Effective Output Capacitance, Time Related <sup>b</sup>	C <sub>o(tr)</sub>			-	293	-		
Total Gate Charge	Qg	V <sub>GS</sub> = 10 V I <sub>D</sub> = 11 A, V <sub>DS</sub> = 520 V			-	71	-	
Gate-Source Charge	Q <sub>gs</sub>			-	14	-	nC	
Gate-Drain Charge	Q <sub>gd</sub>				-	33	-	1
Turn-On Delay Time	t <sub>d(on)</sub>		•		-	22	-	
Rise Time	t <sub>r</sub>		= 520 V, I <sub>D</sub> = 11 A,		-	34	-	ns
Turn-Off Delay Time	t <sub>d(off)</sub>		= 10 V, $R_g = 9.1 \Omega$		-	68	-	
Fall Time	t <sub>f</sub>			-	42	-	1	
Gate Input Resistance	R <sub>g</sub>	f = 1	MHz, open drain		-	0.78	-	Ω
Drain-Source Body Diode Characteristic								
Continuous Source-Drain Diode Current	۱ <sub>S</sub>	MOSFET symbol showing the integral reverse p - n junction diode		-	-	21		
Pulsed Diode Forward Current	I <sub>SM</sub>			-	-	53	A	
Diode Forward Voltage	V <sub>SD</sub>	T <sub>J</sub> = 25 °C, I <sub>S</sub> = 11 A, V <sub>GS</sub> = 0 V		-	0.9	1.2	v	
Reverse Recovery Time	t <sub>rr</sub>	$T_{J} = 25 \text{ °C}, I_{F} = I_{S} = 11 \text{ A},$ dl/dt = 100 A/µs, V <sub>R</sub> = 25 V			-	160	-	ns
Reverse Recovery Charge	Q <sub>rr</sub>				-	1.2	-	μΟ
Reverse Recovery Current	I <sub>RRM</sub>			v	-	14	<u> </u>	A

Notes

a.  $C_{oss(er)}$  is a fixed capacitance that gives the same energy as  $C_{oss}$  while  $V_{DS}$  is rising from 0 % to 80 %  $V_{DSS}$ . b.  $C_{oss(tr)}$  is a fixed capacitance that gives the same charging time as  $C_{oss}$  while  $V_{DS}$  is rising from 0 % to 80 %  $V_{DSS}$ .



#### TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)

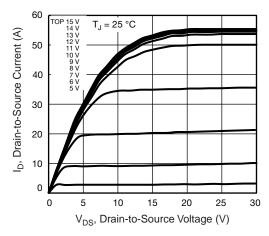


Fig. 1 - Typical Output Characteristics

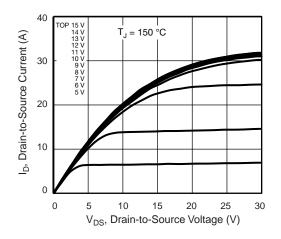


Fig. 2 - Typical Output Characteristics

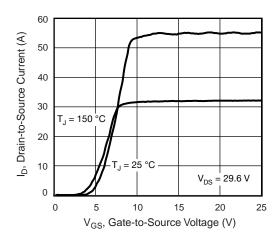


Fig. 3 - Typical Transfer Characteristics

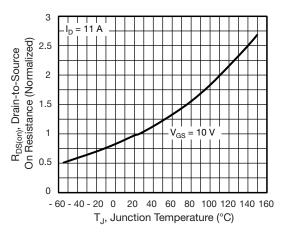


Fig. 4 - Normalized On-Resistance vs. Temperature

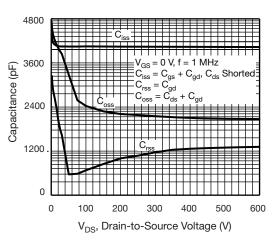


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage

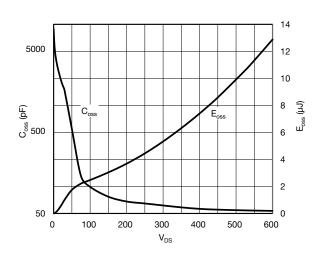


Fig. 6 -  $C_{oss}$  and  $E_{oss}$  vs.  $V_{DS}$ 

### VBM165R18



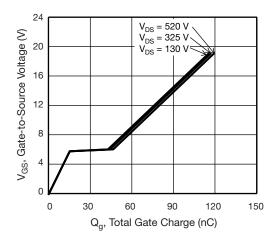


Fig. 7 - Typical Gate Charge vs. Gate-to-Source Voltage

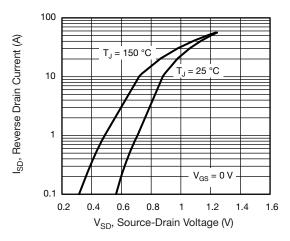


Fig. 8 - Typical Source-Drain Diode Forward Voltage

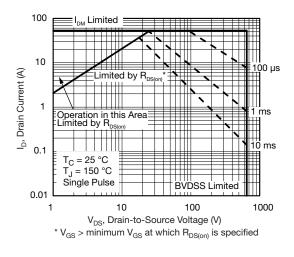


Fig. 9 - Maximum Safe Operating Area

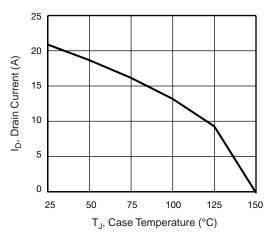


Fig. 10 - Maximum Drain Current vs. Case Temperature

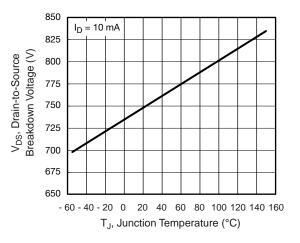


Fig. 11 - Temperature vs. Drain-to-Source Voltage



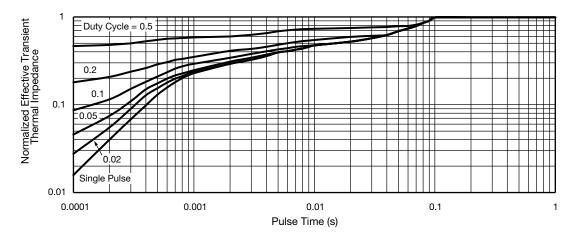


Fig. 12 - Normalized Thermal Transient Impedance, Junction-to-Case

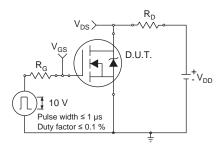


Fig. 13 - Switching Time Test Circuit

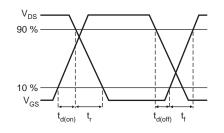


Fig. 14 - Switching Time Waveforms

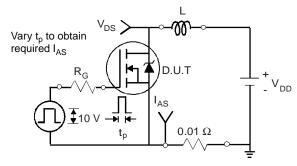


Fig. 15 - Unclamped Inductive Test Circuit

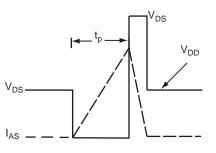


Fig. 16 - Unclamped Inductive Waveforms

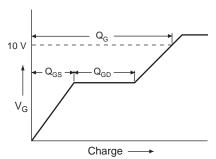


Fig. 17 - Basic Gate Charge Waveform

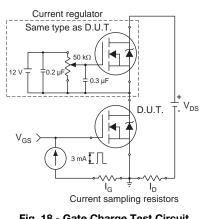
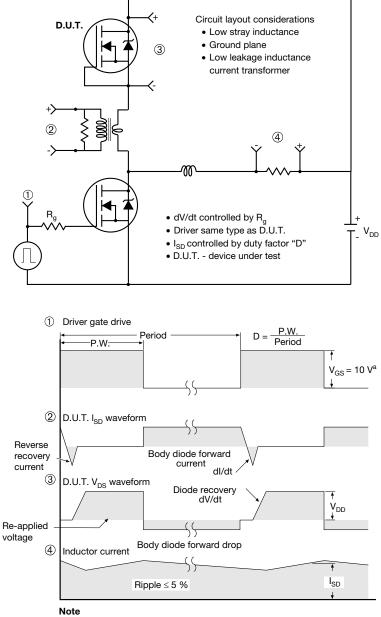


Fig. 18 - Gate Charge Test Circuit



#### Peak Diode Recovery dV/dt Test Circuit

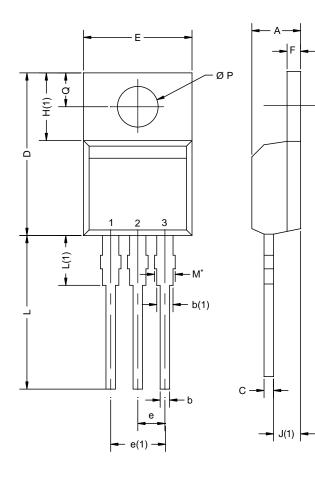


a.  $V_{GS} = 5$  V for logic level devices

Fig. 19 - For N-Channel



## **TO-220AB**



	MILLIMETERS		INC	HES	
DIM.	MIN.	MAX.	MIN.	MAX.	
А	4.25	4.65	0.167	0.183	
b	0.69	1.01	0.027	0.040	
b(1)	1.20	1.73	0.047	0.068	
С	0.36	0.61	0.014	0.024	
D	14.85	15.49	0.585	0.610	
Е	10.04	10.51	0.395	0.414	
е	2.41	2.67	0.095	0.105	
e(1)	4.88	5.28	0.192	0.208	
F	1.14	1.40	0.045	0.055	
H(1)	6.09	6.48	0.240	0.255	
J(1)	2.41	2.92	0.095	0.115	
L	13.35	14.02	0.526	0.552	
L(1)	3.32	3.82	0.131	0.150	
ØР	3.54	3.94	0.139	0.155	
Q	2.60	3.00	0.102	0.118	
ECN: X12- DWG: 547	0208-Rev. N, (	08-Oct-12			

#### Notes

 $^{\star}$  M = 1.32 mm to 1.62 mm (dimension including protrusion) Heatsink hole for HVM

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